



# **Soldering Technology for High and *Ultra High* Temperature Service**

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\*Sandia is a multiprogram laboratory operated by Sandia Corporation, a Lockheed Martin Company, for the US Dept. of Energy's National Nuclear Security Administration under contract DE-AC04-94AL85000.



# Outline

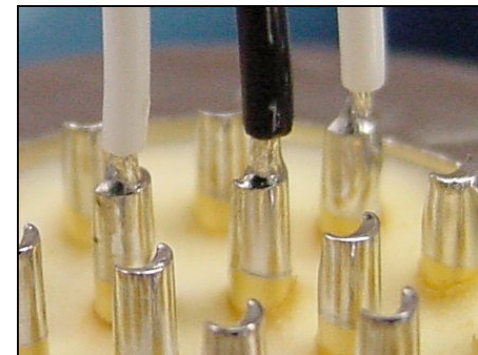
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- **Introduction**

- The case for *soldering technology*
- Service environments
- Process definition

- **Approach**

- Commercially-available, ultra high temperature solders
- New solder alloy compositions
- Candidate base materials



- **Accomplishments**



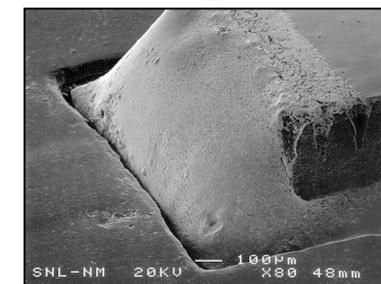
## Introduction

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- In 2002, it was anticipated that, within five years (2007), electronic devices, substrates, and power supplies would become available for **ultra high temperature** applications\*.

\*The term **ultra high temperature** refers to service environments having sustained temperatures of **300°C (572°F)** and short-term, temperature excursions as high as **350°C (662°F)**.

- In a 2002 white paper, the groundwork was set by which Sandia National Laboratories would investigate **soldering technology** for the assembly of printed circuit boards to be used in electronic products for ultra high temperature applications\*\*.

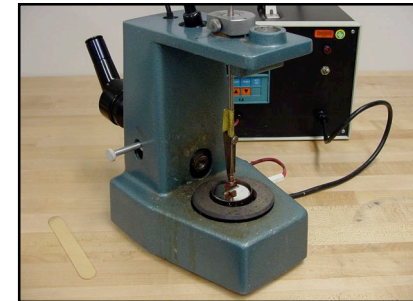


\*\*P. Vianco, "Solder Interconnect Technology for Ultra-High Temperature Applications," *Sandia Report SAND2002-2948*, Sandia National Laboratories, Albuquerque, NM, 2002).

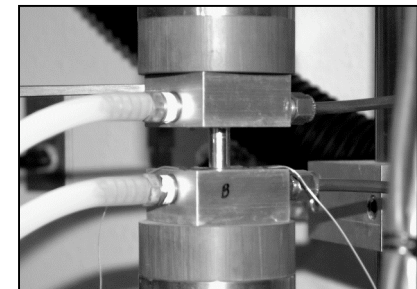
# Introduction

- **Sandia capabilities:**

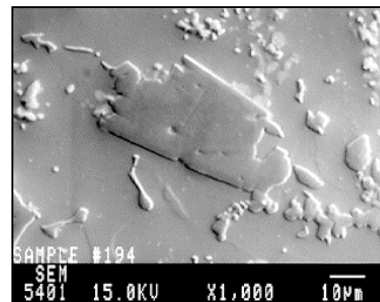
- Knowledge-base and experience with the development of new solder compositions.
- **Solderability testing**, **mechanical properties**, and **differential scanning calorimetry (DSC)** for alloy and process development efforts.
- Analysis capabilities to characterize the solder physical metallurgy as well as the microstructural features of interconnections made to selected base materials.



*Solderability testing*



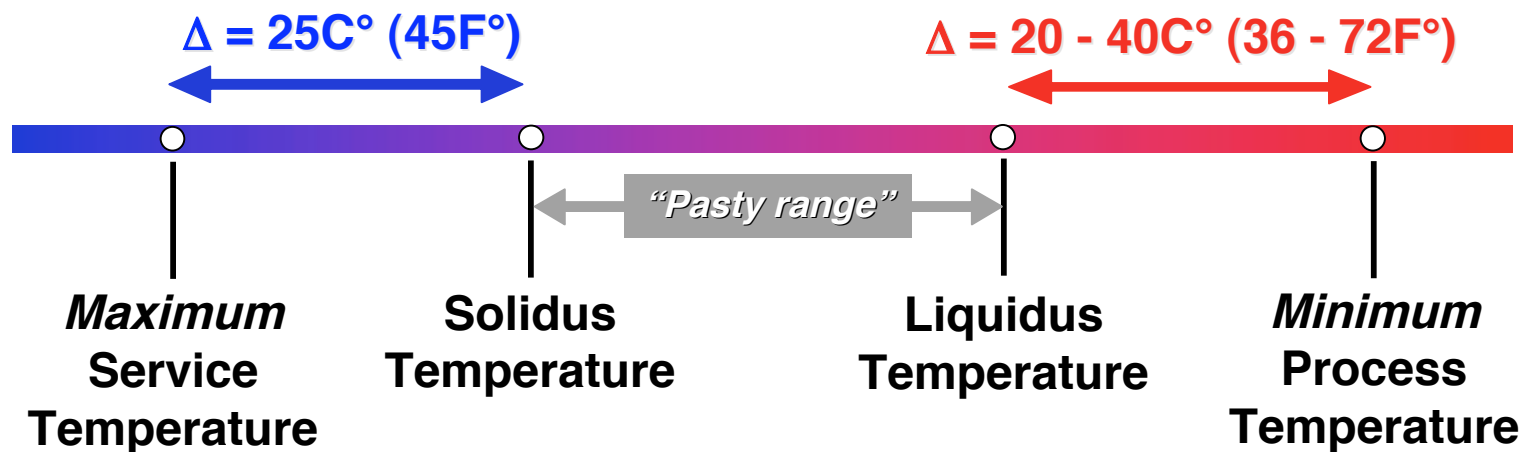
*Mechanical properties*



*Microstructure  
characterization*

## Introduction

The service environment benchmarks the physical and mechanical properties required of the solder alloy(s).



### Solder melting properties:

**350°C**  
(662°F)

Ultra high  
temperature  
service



**375°C**  
(707°F)

*0C° (eutectic)* . . . **375°C** (707°F)

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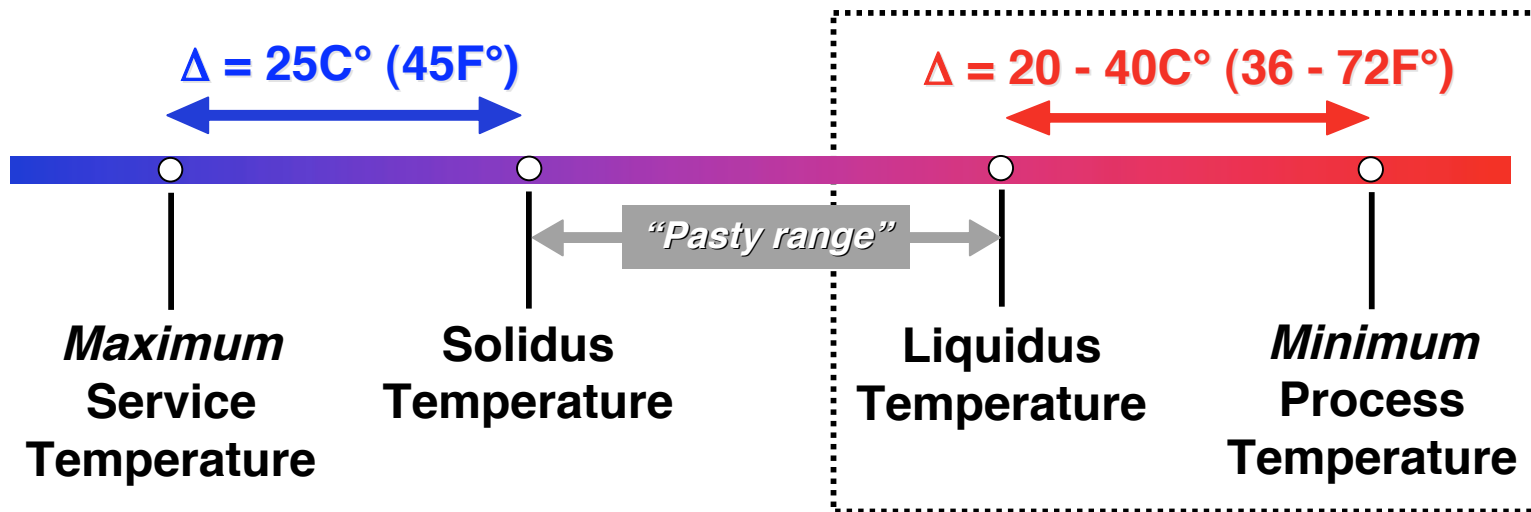
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*50C° (90F°)* . . . **425°C** (797°F)



## Introduction

The melting properties of the solder alloy(s) benchmark the minimum, peak assembly processing temperature(s).



**Peak processing temperature:**

375°C (707°F)	395°C (743°F)
⋮	⋮
⋮	➡
⋮	⋮
425°C (797°F)	445°C (833°F)

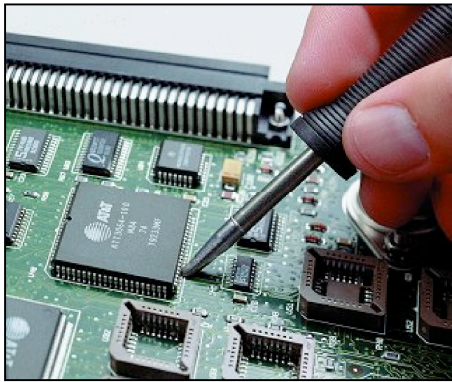




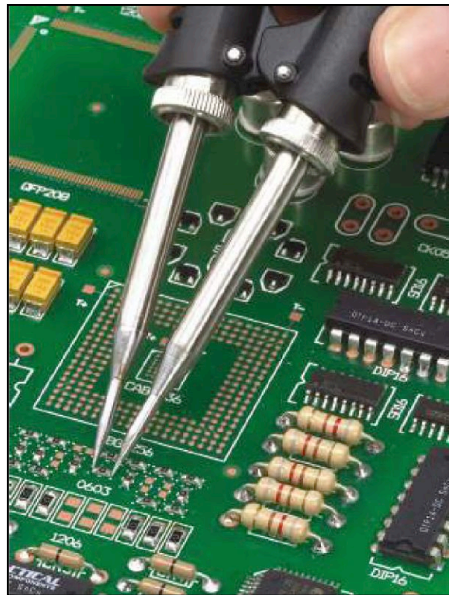
## Introduction

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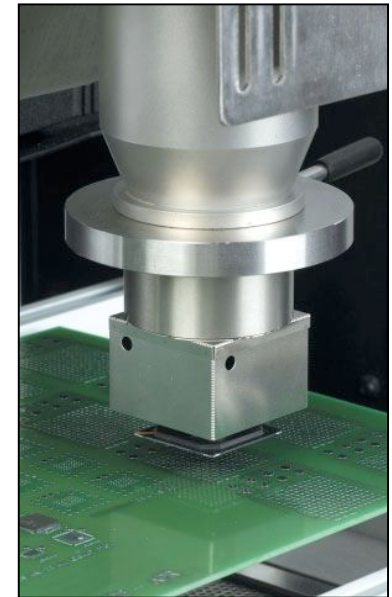
- The process definition includes, identifying the most suitable soldering technique(s) for the product types.
- **Hand soldering** provides an excellent starting point, particularly for prototype development efforts.



Point tip



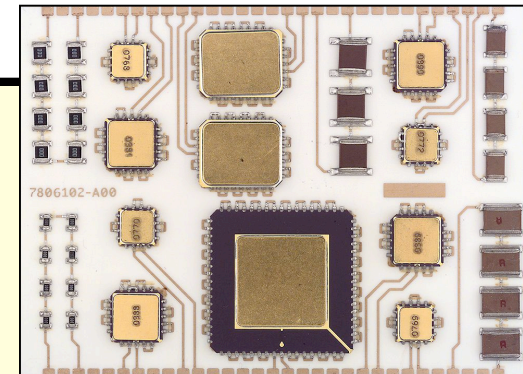
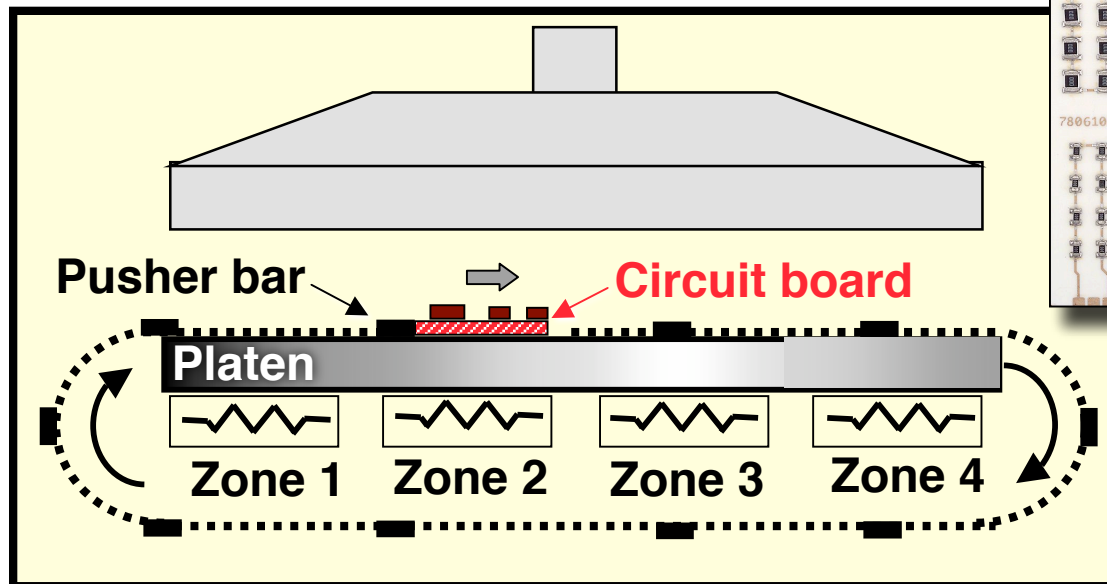
Tweezer tips



Hot gas

## Introduction

- Machine (automated) assembly should also be considered.
- **Conduction soldering** is a potential candidate for the assembly of printed circuit boards .



*Hybrid (ceramic)  
microcircuit  
technology*



## Approach

- Solder compositions for ultra-high temperature service:

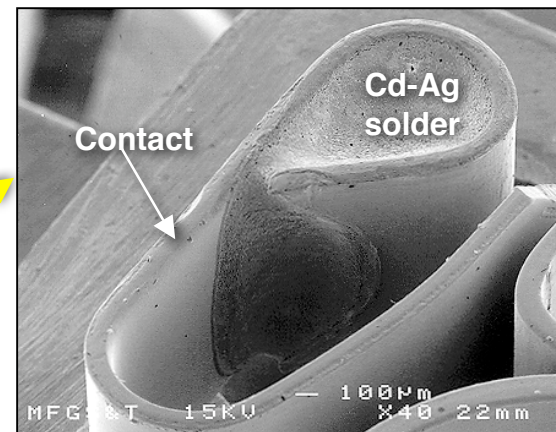
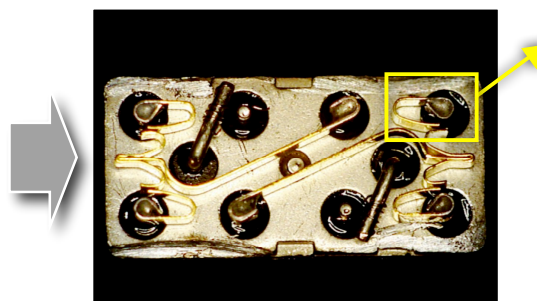
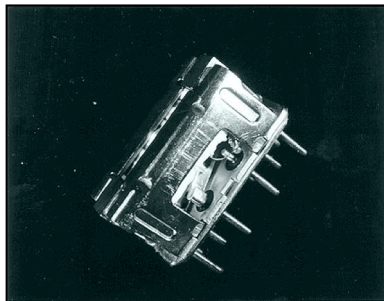
$$395^{\circ}\text{C} (707^{\circ}\text{F}) < T_s \text{ \& } T_l < 445^{\circ}\text{C} (797^{\circ}\text{F})$$

Consider both **RoHS** and *non-RoHS* compliant materials.

- Commercially-available solder alloys (wt.%):

100Zn	$T_s = 420^{\circ}\text{C} (788^{\circ}\text{F})$	$T_l = 420^{\circ}\text{C} (788^{\circ}\text{F})$
→ 95Cd-5Ag	$T_s = 343^{\circ}\text{C} (649^{\circ}\text{F})$	$T_l = 393^{\circ}\text{C} (739^{\circ}\text{F})$

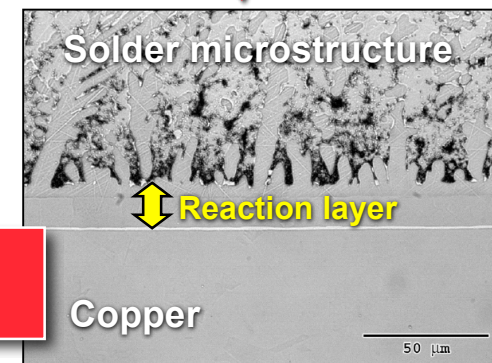
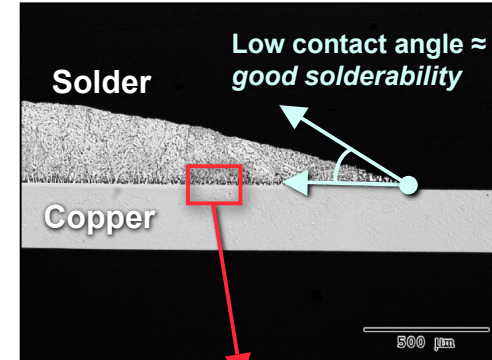
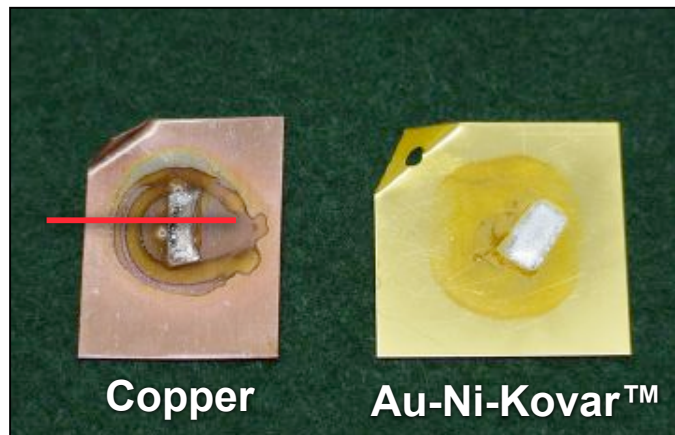
The Cd-Ag solder is used primarily in the construction of relay devices.



## Approach

- New solder alloy development has considered Zn-based compositions having the appropriate melting properties.
- **Bench-top evaluations:**

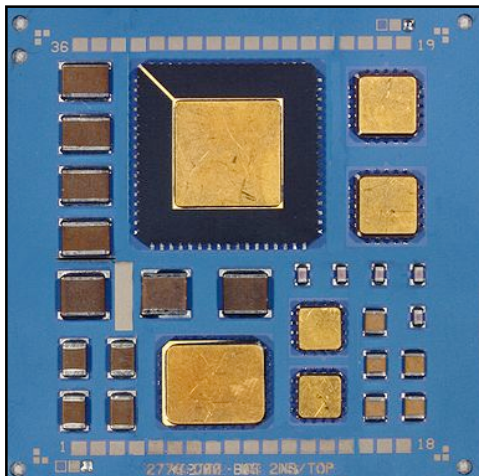
Sessile drop tests provide a very efficient methodology to evaluate **solderability**, **fluxes**, and the joint **microstructures**.



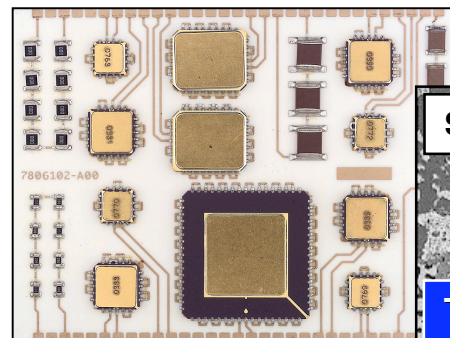
**Metallographic cross sections**

## Approach

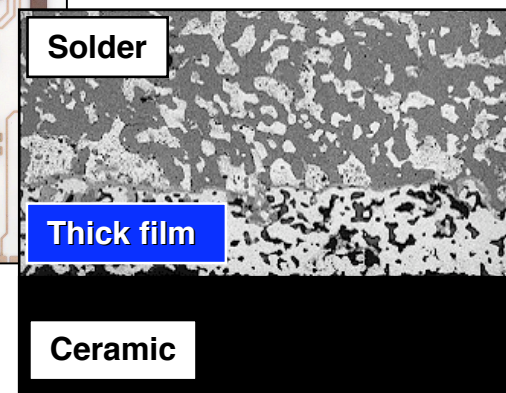
- **Ceramic substrates** provide suitable base materials for ultra high temperature applications; candidates include:
  - **alumina**,
  - **beryllia**,
  - **aluminum nitride**, and
  - **low-temperature co-fired ceramic (LTCC)**.
- Both **thick film ink** and deposited **thin film layers** would provide suitable conductor technologies.



*Low-temperature co-fired ceramic (LTCC)*



*Alumina*





## Accomplishments

- During the development of ultra high temperature solders, efforts have also addressed Pb-based, **high temperature solders** for advanced prototype development.

$$295^{\circ}\text{C} (563^{\circ}\text{F}) < T_s \text{ \& } T_l < 345^{\circ}\text{C} (653^{\circ}\text{F})$$

- The candidate alloys are:

95Pb-5Sn	$T_s = 308^{\circ}\text{C} (586^{\circ}\text{F})$	$T_l = 312^{\circ}\text{C} (594^{\circ}\text{F})$
97.5Pb-2.5Ag	$T_s = 304^{\circ}\text{C} (580^{\circ}\text{F})$	$T_l = 380^{\circ}\text{C} (716^{\circ}\text{F})$

- The particular application was the attachment of Ni plated wires to chip capacitor terminations.

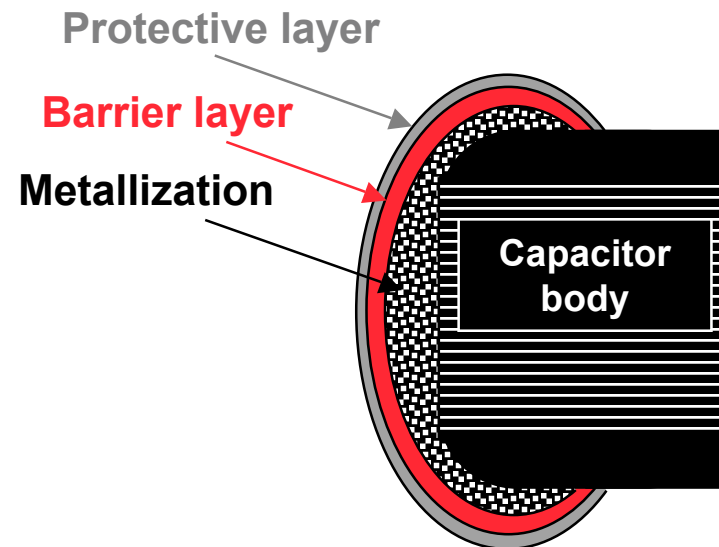
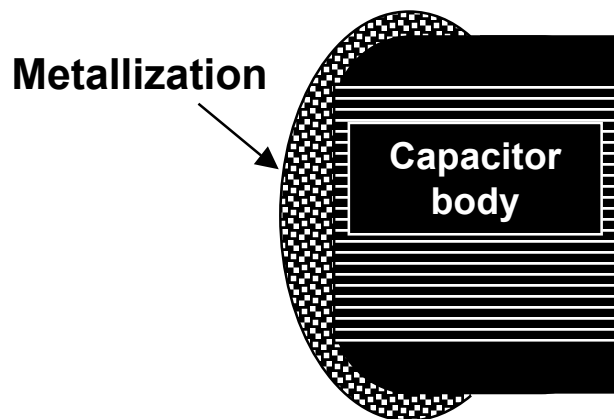




## Accomplishments

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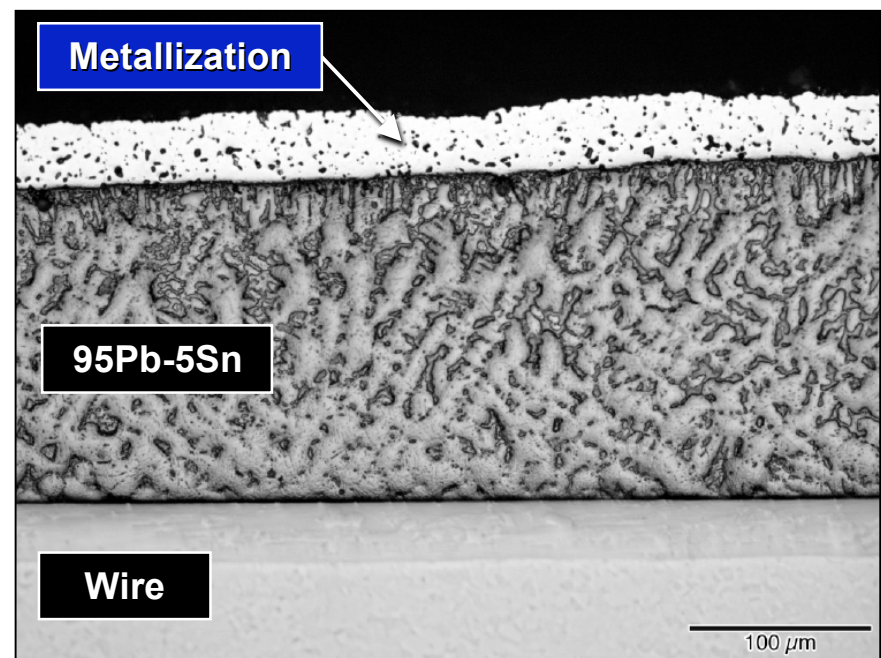
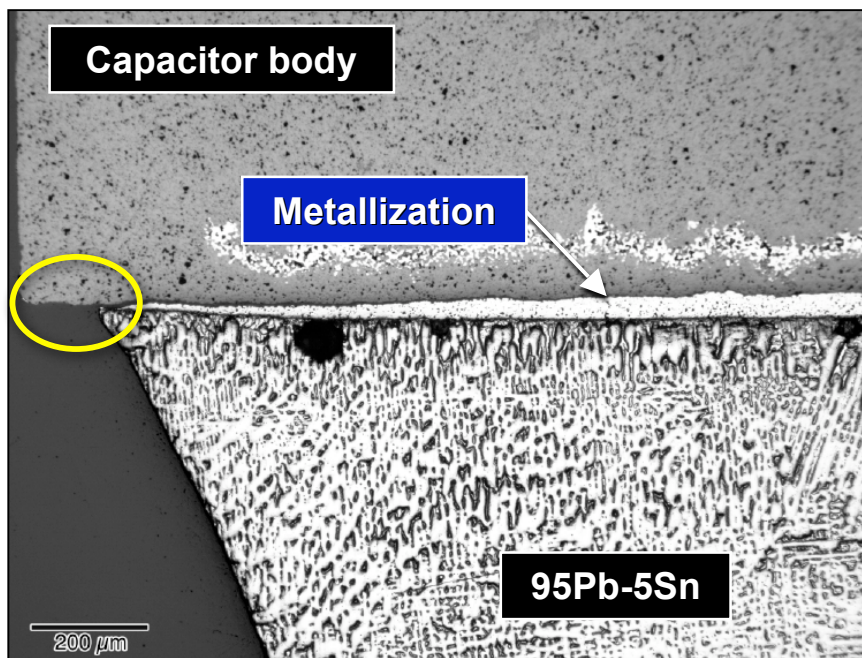
- Concerns that were raised in this study included:
  - Metallization dissolution in the absence of a barrier layer (Ni or Cu).
  - Fracture at the interface between the metallization and capacitor body





## Accomplishments

Metallization dissolution was minimized during the process to attach the wire using either of the Pb-based solders.

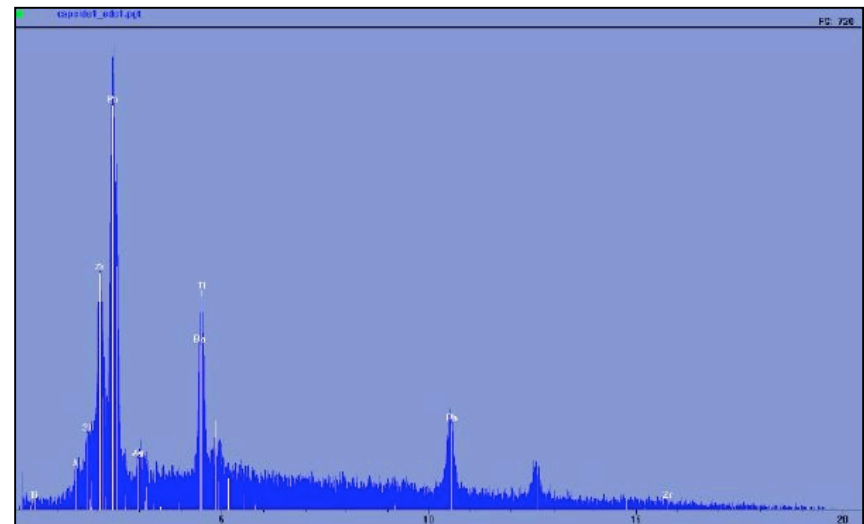
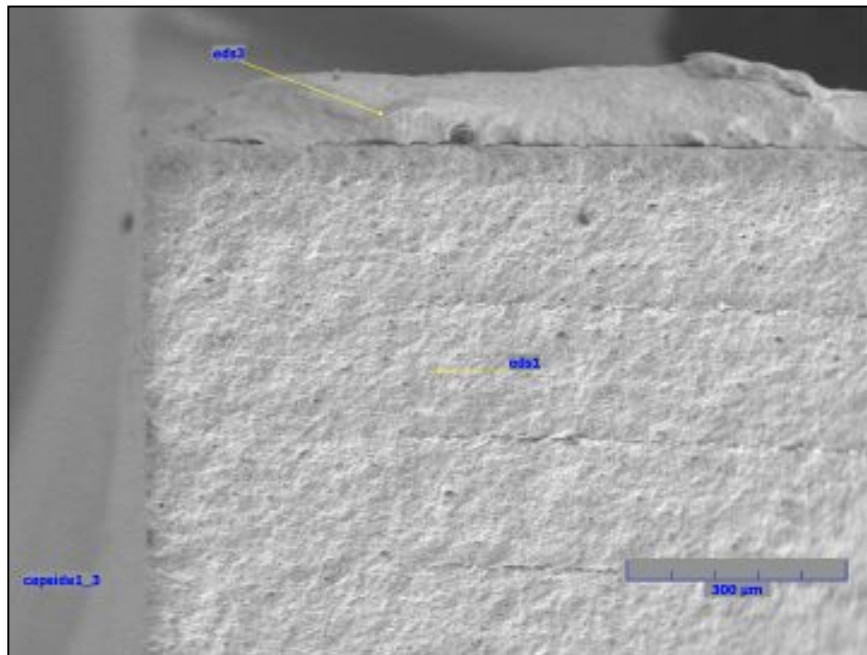






## Accomplishments

- The wires easily detached from the capacitor terminations.
- The fracture surfaces were evaluated by SEM/EDXA.

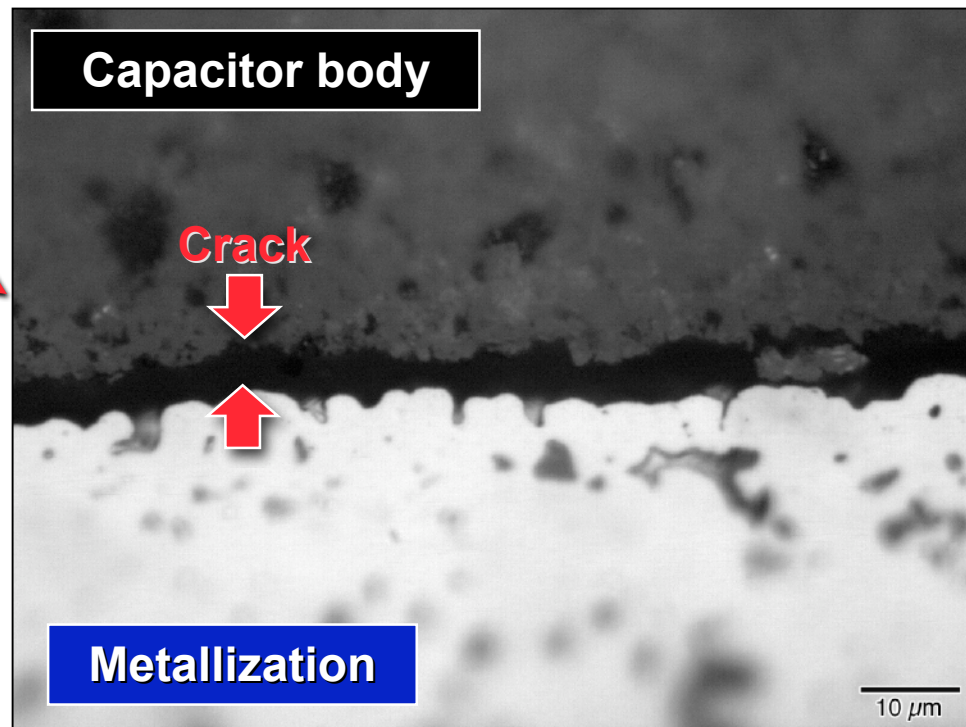
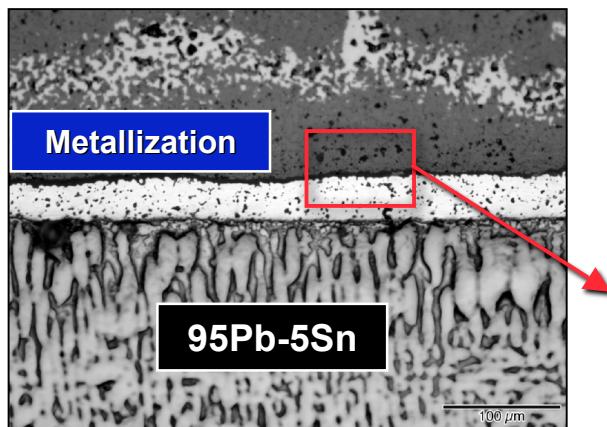


**Constituents of the capacitor body:  
Ag, Ba, Ti, Pb, and Zr.**

- Potential fracture locations:  $\left\{ \begin{array}{l} (1) \text{ metallization/capacitor interface or} \\ (2) \text{ bulk capacitor body} \end{array} \right.$

## Accomplishments

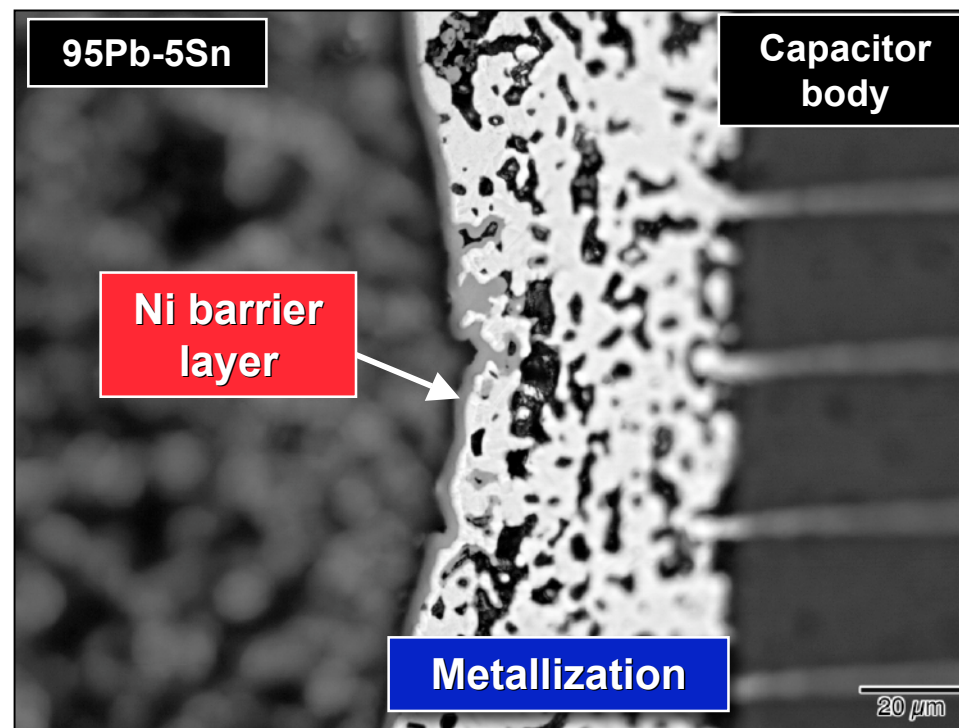
- Poor adhesion between the metallization and the capacitor body was confirmed - the likely source was thermal shock.
- Fracture did *not* occur in the bulk capacitor body.





## Accomplishments

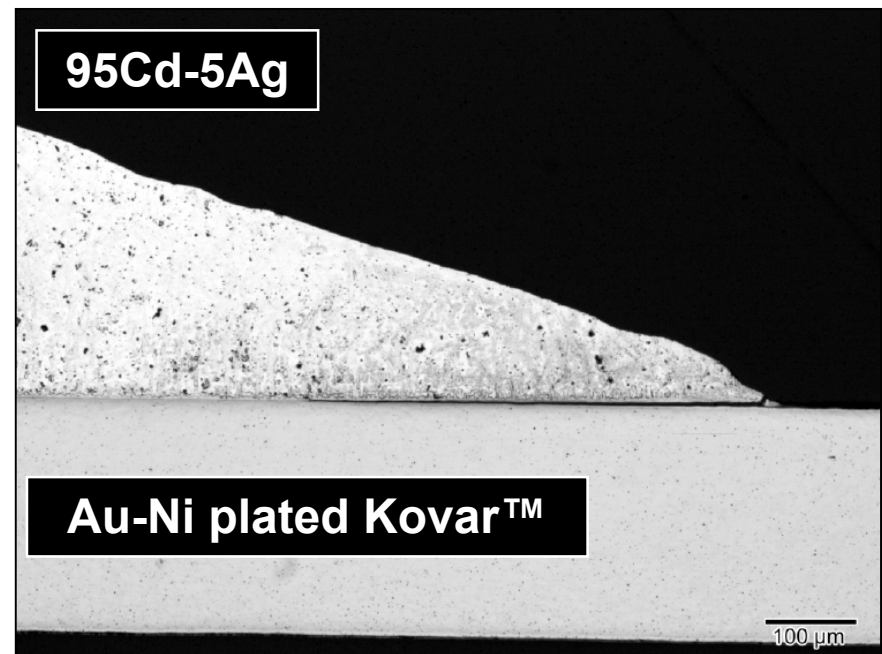
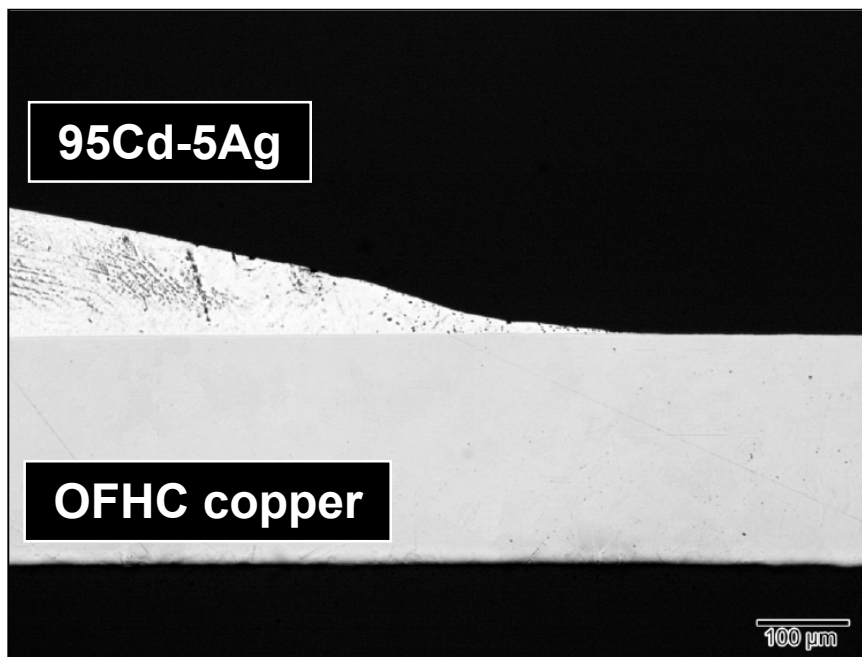
- A second set of capacitors having a Ni barrier layer exhibited no significant metallization dissolution and ... *fortuitously* ... good adhesion of the metallization layer.





## Accomplishments

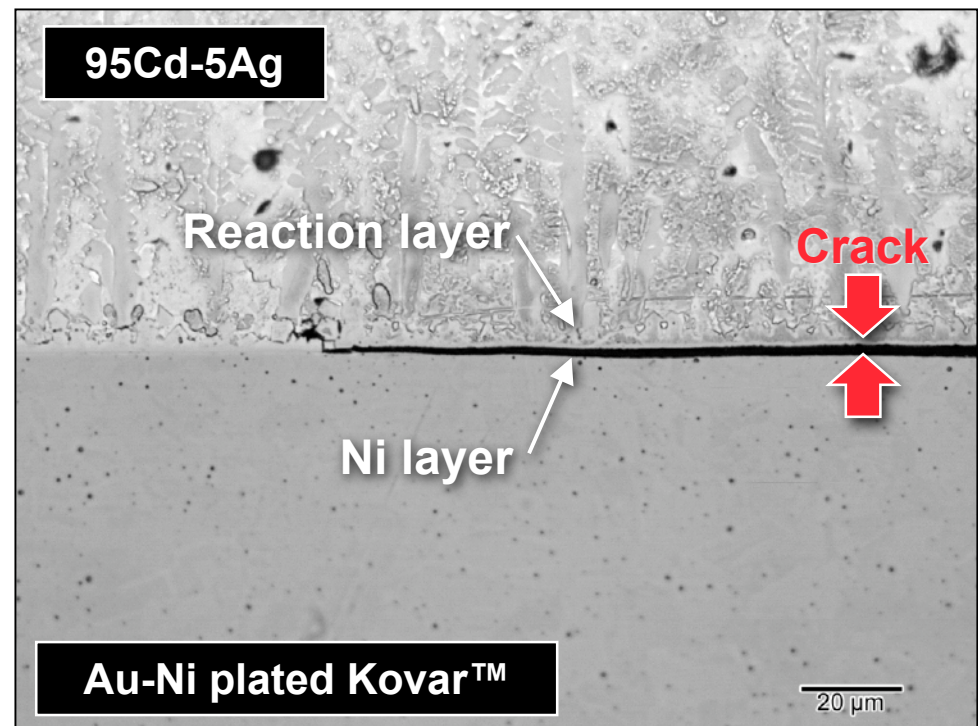
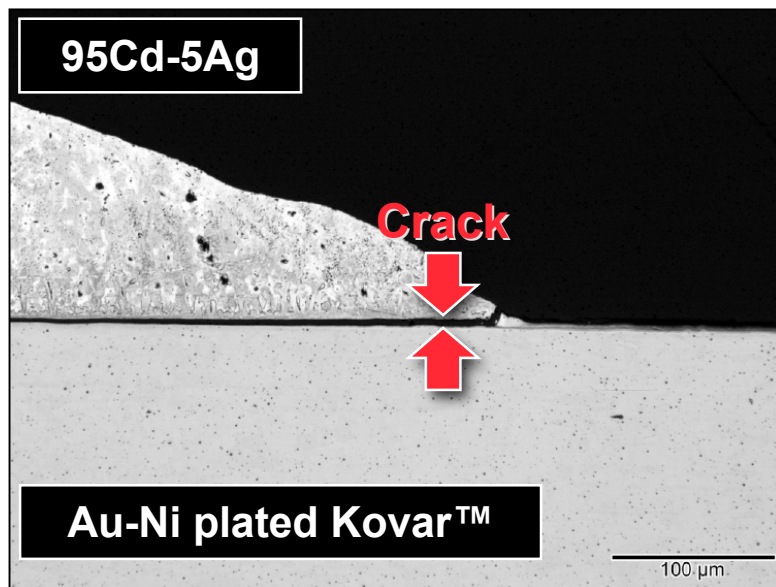
- The 95Cd-5Ag solder exhibited excellent solderability on both OFHC copper and Au-Ni plated Kovar™ base materials.





## Accomplishments

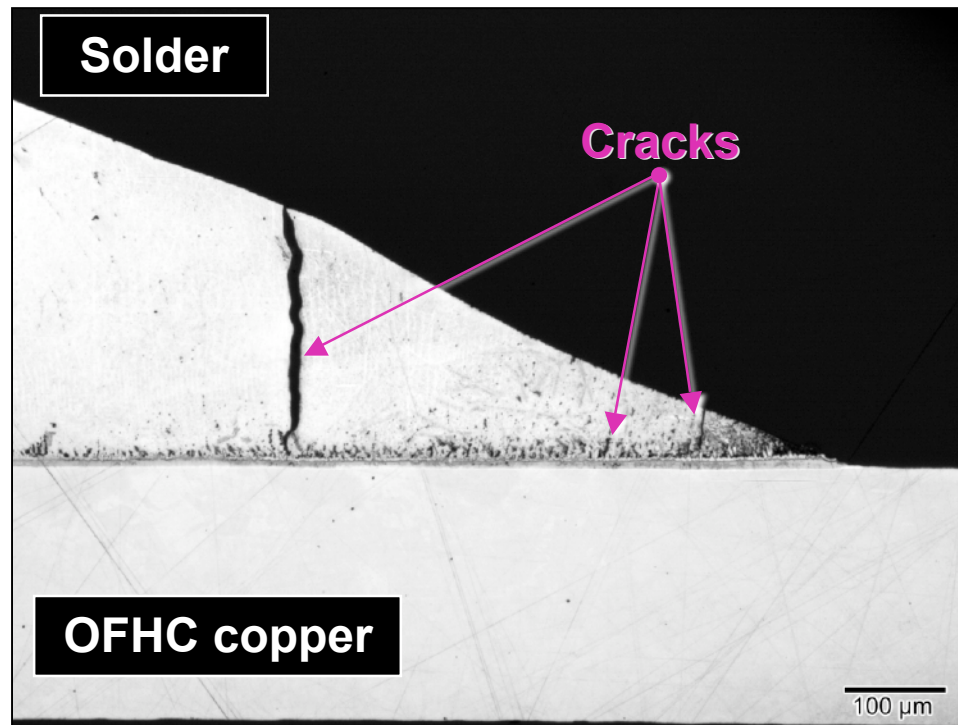
- Good integrity was observed at the 95Cd-5Sn/OFHC copper interface; however, **cracking** occurred at the 95Cd-5Ag/Ni interface of the Au-Ni plated Kovar™ base material.





## Accomplishments

- Similar **interface cracks** have been observed between **Zn-based solders** and Au-Ni plated Kovar™ base material.
- The **Zn-based solders** also exhibited “**hot-cracking**” due to the formation of low-melting, grain boundary phases.





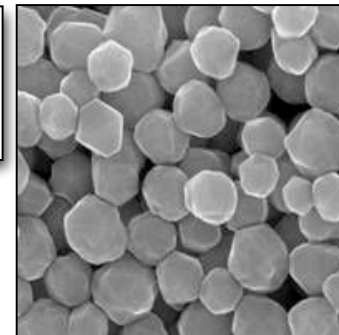


## Accomplishments

- Advanced interconnection technologies that are being explored, include **transient liquid phase (TLP) bonding** as well as **nano-particle**-based filler metals that allow ...
- **Low melting temperature solder alloys** for assembly process to limit thermal degradation of heat sensitive components
- **High melting temperature solder joints** to provide the long-term reliability needed at elevated service temperatures.

Nano-particle-based solders may provide this capability at reasonable, per-unit cost.

**Nano-sized particles melt at considerably lower temperatures than the bulk material.**



200 nm  
Ni powder